

Notice of References Cited

Application/Control No.

10/569,968

Applicant(s)/Patent Under

Reexamination

DEMIR ET AL.

Examiner

RICARDO E. LOPEZ

Art Unit

1786

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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